#### THAT 300 Series

### **FEATURES**

- 4 Matched NPN Transistors (300)
  - 4 Matched PNP Transistors (320)
  - 2 Matched NPNs and PNPs (340)
  - 4 Matched NP6N 4 Matched PNP (380)
- Monolithic Construction
- Low Noise
  - $0.75 \, nV/\sqrt{Hz} \, (PNP)$
  - $0.8 \, \text{nV} / \sqrt{\text{Hz}} \, (\text{NPN})$
- High Speed

  - $f_T = 350 \text{ MHz (NPN)}$   $f_T = 325 \text{ MHz (PNP)}$
- Excellent Matching 500 μV typical between devices of same gender
- Dielectrically Isolated
- $36V V_{\text{CEO}}$

#### **APPLICATIONS**

- Microphone Preamplifiers
- **Current Sources**
- **Current Mirrors**
- Log/Antilog Amplifiers
- Multipliers
- Servos

### DESCRIPTION

The THAT300 Series ICs are large-geometry monolithic NPN and/or PNP transistor arrays which combine low noise, high speed and excellent parametric matching between devices of the same gender. The large geometries typically result in 25  $\Omega$  base spreading resistance for the PNP devices (30  $\Omega$  for the NPNs), producing  $0.75 \, nV/\sqrt{Hz}$  voltage noise  $(0.8 \text{ nV}/\sqrt{\text{Hz}} \text{ for the NPNs})$ . This makes the 300 Series an ideal choice for low-noise amplifier input

Fabricated on a Complementary Bipolar Dielectrically Isolated process, each transistor is electri-

cally isolated from the others by a layer of insulating oxide. The resulting low collector-to-substrate capacitance produces a typical NPN f<sub>T</sub> of 350 MHz, 325 MHz for the PNPs. This delivers ac performance similar to discrete 2N3904- and 2N3906-class devices. Dielectric isolation also minimizes crosstalk and provides complete DC isolation.

Substrate biasing is not required for normal operation, though the substrate should be grounded to optimize speed and minimize inter-device crosstalk. The monolithic construction assures excellent parameter matching and tracking over temperature.

Part Number	Configuration	Package
ТНАТЗООР	4 Mateka d NIDNI Tunna jatana	DIP14
THAT300S	4-Matched NPN Transistors	SO14
THAT320P	4 Match ad DND Transisters	DIP14
THAT320S	4- Matched PNP Transistors	SO14
THAT340P	2 Matched NPN Transistors and	DIP14
THAT340S	2 Matched PNP Transistors	SO14
THAT380G	4 Matched NPN Transistors and 4 Matched PNP Transistors	Individual Die

Table 1. Ordering Info

### SPECIFICATIONS 1

	Maxi	mum Ratings (T	$\Delta = 25^{\circ}C$			
Parameter	Symbol	Conditions	Min	Тур	Max	Units
NPN Collector-Emitter Voltage	BV <sub>CEO</sub>	$I_C = 1 \text{ mAdc}, I_B = 0$	36	40		V
NPN Collector-Base Voltage	BV <sub>CBO</sub>	$I_C = 10 \mu Adc, I_E = 0$	36	40	_	V
NPN Emitter-Base Voltage	$BV_{EBO}$	$I_{E} = 100 \ \mu Adc, I_{C} = 0$	5	_		V
NPN Collector Current	I <sub>C MAX</sub>		10	20		mA
NPN Emitter Current	I <sub>E MAX</sub>		10	20		mA
PNP Collector-Emitter Voltage	BV <sub>CEO</sub>	$I_C = 1 \text{ mAdc}, I_B = 0$	-36	-40	14	V
PNP Collector-Base Voltage	BV <sub>CBO</sub>	$I_{C} = 10 \mu Adc, I_{E} = 0$	-36	-40		V
PNP Emitter-Base Voltage	$BV_{EBO}$	$I_{E} = 100 \ \mu Adc, I_{C} = 0$	-5	_		V
PNP Collector Current	I <sub>C MAX</sub>		-10	-20		mA
PNP Emitter Current	I <sub>E MAX</sub>		-10	-20		mA
Collector-Collector Voltage	BV <sub>CC</sub>		±100	±200	_	V
Emitter-Emitter Voltage	BV <sub>EE</sub>		±100	±200	_	V
Operating Temperature Range	T <sub>A</sub>		0		70	°C
Maximum Junction Temperature	T <sub>JMAX</sub>				150	°C
Storage Temperature	T <sub>STORE</sub>		-45		125	°C

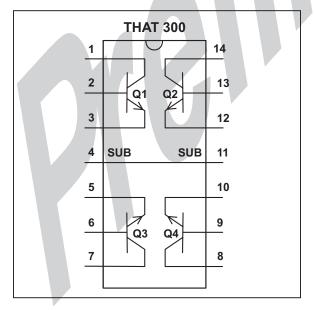


Fig 1. 300 Pinout

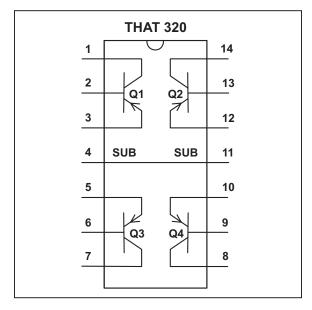
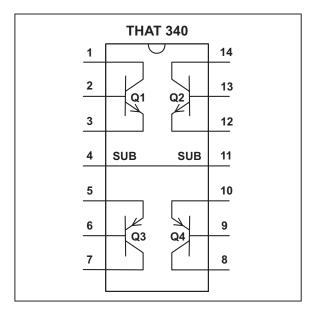


Fig 2. 320 Pinout

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# SPECIFICATIONS<sup>1</sup> (Cont'd)



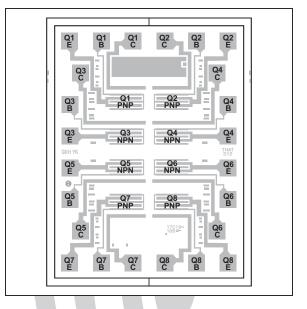


Fig 3. 340 Pinout

Fig 4. 380 Die layout

NPN Electrical Characteristics <sup>2</sup>							
Parameter	Symbol	Conditions	Min	Тур	Max	Units	
NPN Current Gain	h <sub>fe</sub>	V <sub>CB</sub> = 10 V	1				
		$I_C = 1 \text{ mA}$	60	100	_		
		I <sub>C</sub> = 10 μA		100	_		
NPN Current Gain Matching	$\Delta h_fe$	$V_{CB} = 10 \text{ V, } I_{C} = 1 \text{ mA}$	_	5	_	%	
NPN Noise Voltage Density	e <sub>N</sub>	$V_{CB} = 10 \text{ V}, I_C = 1 \text{ mA}, 1 \text{ kHz}$	_	0.8	_	nV/√Hz	
NPN Gain-Bandwidth Product	f <sub>T</sub>	$I_{C} = 1 \text{ mA}, V_{CB} = 10 \text{ V}$		350		MHz	
NPN ΔV <sub>BE</sub> (THAT300: V <sub>BE1</sub> -V <sub>BE2</sub> ;	V <sub>BE3</sub> -V <sub>BE4</sub> ) (T	'HAT340: V <sub>BE1</sub> -V <sub>BE2</sub> )					
	Vos	$I_C = 1 \text{ mA}$	_	±0.5	±3	mV	
	<i>7</i> T	I <sub>C</sub> = 10 μA	_	±0.5		mV	
NPN ΔI <sub>B</sub> (THAT300: I <sub>B1</sub> -I <sub>B2</sub> , I <sub>B3</sub> -I <sub>B</sub>	<sub>4</sub> ) (THAT340:	I <sub>B1</sub> -V <sub>B2</sub> )					
	Ios	$I_C = 1 \text{ mA}$	_	±500	±1500	nA	
		$I_C = 10 \mu A$	_	±5		nA	
NPN Collector-Base Leakage Cu	ırrent I <sub>CBO</sub>	V <sub>CB</sub> = 25 V	_	25	_	рА	
NPN Bulk Resistance	r <sub>BE</sub> √	$I_{CB} = 0 \text{ V}, 10  \mu\text{A} < I_{C} < 10 \text{ mA}$	_	2	_	Ω	
NPN Base Spreading Resistance	e r <sub>bb</sub>	$V_{CB}$ = 10 V, $I_C$ = 1 mA	_	30	_	Ω	
NPN Collector Saturation Voltage	e V <sub>CE(SAT)</sub>	I <sub>C</sub> = 1 mA, I <sub>B</sub> = 100μA	_	0.05		V	
NPN Output Capacitance	C <sub>OB</sub> V	<sub>CB</sub> = 10 V, I <sub>E</sub> = 0 mA, 100 kHz		3		pF	
NPN Collector-CollectorCapacita	nce (THAT30 C <sub>CC</sub>	00: Q1-Q2, Q3-Q4) (THAT340: V <sub>CC</sub> = 0 V, 100 kHz	Q1-Q2)	0.7		pF	

<sup>1.</sup> All specifications subject to change without notice.

<sup>2.</sup> Unless otherwise noted,  $T_A$ =25°C.

## SPECIFICATIONS<sup>1</sup> (Cont'd)

	PNP	Electrical Character	istics <sup>2</sup>			
Parameter	Symbol	Conditions	Min	Тур	Max	Units
PNP Current Gain	h <sub>fe</sub>	V <sub>CB</sub> = 10 V				
		$I_C = 1 \text{ mA}$	50	75	- 4	
		$I_C = 10 \mu A$		75		
PNP Current Gain Matching	$\Delta h_{\text{fe}}$	$V_{CB}$ = 10 V, $I_{C}$ = 1 mA	_	5		%
PNP Noise Voltage Density	$e_N$	$V_{CB} = 10 \text{ V}, I_{C} = 1 \text{ mA}, 1 \text{ kHz}$	_	0.75		nV/√Hz
PNP Gain-Bandwidth Product	$f_{T}$	$I_{C}$ = 1 mA, $V_{CB}$ = 10 V		325		MHz
PNP ΔV <sub>BE</sub> (THAT320: V <sub>BE1</sub> -V <sub>BE2</sub> ;	V <sub>BE3</sub> -V <sub>BE4</sub> ) (	THAT340: V <sub>BE3</sub> -V <sub>BE4</sub> )				
	$V_{OS}$	I <sub>C</sub> = 1 mA	_ /	±0.5	±3	mV
		I <sub>C</sub> = 10 μA	-4/	±0.5		mV
PNP ΔI <sub>B</sub> (THAT320: I <sub>B1</sub> -I <sub>B2;</sub> I <sub>B3</sub> -I <sub>B4</sub>	) (THAT340	: I <sub>B3</sub> -I <sub>B4</sub> )	. \ \			
	Ios	I <sub>C</sub> = 1 mA	1	±700	±1800	nA
		I <sub>C</sub> = 10 μA	$\rightarrow$	±7		νΑ
PNP Collector-Base						
Leakage Current	I <sub>CBO</sub>	V <sub>CB</sub> = 25 V		-25	_	pA
PNP Bulk Resistance	r <sub>BE</sub>	$V_{CB} = 0 \text{ V}, 10\mu\text{A} < I_{C} < 10 \text{ mA}$		2	_	Ω
PNP Base Spreading Resistance	e r <sub>bb</sub>	$V_{CB} = 10 \text{ V}, I_{C} = 1 \text{ mA}$		25	_	Ω
PNP Collector Saturation Voltage	e V <sub>CE(SAT)</sub>	$I_{C}$ = 1 mA, $I_{B}$ = 100 $\mu$ A		-0.05		V
PNP Output Capacitance	C <sub>OB</sub>	$V_{CB} = 10 \text{ V}, I_{E} = 0 \text{ mA}, 100 \text{ kHz}$		3		pF
PNP Collector-Collector Capacita	ance (THAT	320: Q1-Q2; Q3-Q4) (THAT340: V <sub>CC</sub> = 0 V, 100 kHz	Q3-Q4)	0.6		pF

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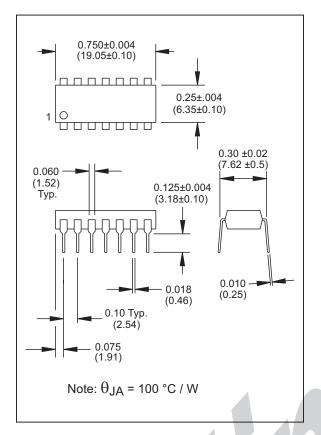
#### CAUTION: THIS IS AN ESD (ELECTROSTATIC DISCHARGE) SENSITIVE DEVICE.

It can be damaged by the currents generated by electrostatic discharge. Static charge and therefore dangerous voltages can accumulate and discharge without detection causing a loss of function or performance to occur.

The transistors in this device are unprotected in order to maximize performance and flexibility. They are more sensitive to ESD damage than many other ICs which include protection devices at their inputs. Note that all of the pins (not just the "inputs") are susceptible.

Use ESD preventative measures when storing and handling this device. Unused devices should be stored in conductive packaging. Packaging should be discharged to the destination socket before the devices are removed. ESD damage can occur to these devices even after they are installed in a board-level assembly. Circuits should include specific and appropriate ESD protection.

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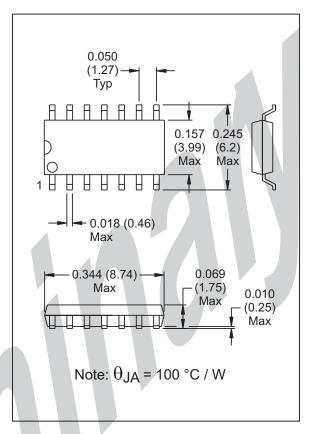


Figure 5. Dual-In-Line Package Outline

Figure 6. Surface-Mount Package Outline

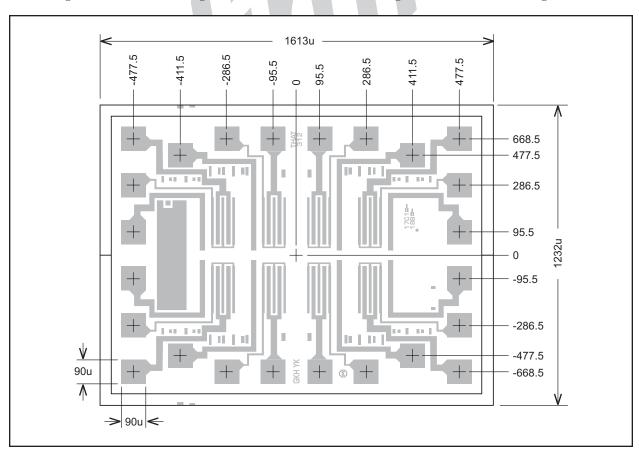


Figure 7. Die dimensions